

POWER MOSFET THRU-HOLE (TO-257AA)

100V, N-CHANNEL HEXFET® MOSFET TECHNOLOGY

Product Summary

Part Number	RDS(on)	I _D	Eyelets
IRFY140C	0.077Ω	16A*	Ceramic
IRFY140CM	0.077Ω	16A*	Ceramic



Description

HEXFET® MOSFET technology is the key to IR Hirel advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high trans conductance. HEXFET® transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

Features

- Simple Drive Requirements
- · Hermetically Sealed
- · Electrically Isolated
- · Ceramic Eyelets
- Ideally Suited For Space Level Applications
- ESD Rating: Class 2 per MIL-STD-750, Method 1020

Absolute Maximum Ratings

Symbol	Parameter	Value	Units	
I_{D1} @ V_{GS} = 10V, T_{C} = 25°C	Continuous Drain Current	16*		
I _{D2} @ V _{GS} = 10V, T _C = 100°C	Continuous Drain Current	16*	Α	
I _{DM} @T _C = 25°C	Pulsed Drain Current ①	64		
P _D @T _C = 25°C	Maximum Power Dissipation	100	W	
	Linear Derating Factor	0.8	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy ②	230	mJ	
I _{AR}	Avalanche Current ①	16*	Α	
E _{AR}	Repetitive Avalanche Energy ①	10	mJ	
dv/dt	Peak Diode Recovery 3	5.5	V/ns	
T _J	Operating Junction and	-55 to + 150		
T _{STG}	Storage Temperature Range	-95 (0 + 150	°C	
	Lead Temperature	300(0.063in./1.6mm from case for 10 sec)		
	Weight	4.3 (Typical)	g	

^{*}Current is limited by package For footnotes refer to the page 2.



Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
BV _{DSS}	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_{D} = 1.0mA$	
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.1		V/°C	Reference to 25°C, I _D = 1.0mA	
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.077	Ω	V _{GS} = 10V, I _{D2} = 16A ④	
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Gfs	Forward Transconductance	9.1			S	V _{DS} = 15V, I _{D2} = 16A ④	
I _{DSS}	Zara Cata Valtaga Drain Current			25		$V_{DS} = 80V, V_{GS} = 0V$	
	Zero Gate Voltage Drain Current			250	μA	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$	
I_{GSS}	Gate-to-Source Leakage Forward			100	nA	$V_{GS} = 20V$	
	Gate-to-Source Leakage Reverse			-100	ш	V _{GS} = -20V	
Q_G	Total Gate Charge			59		I _{D1} = 16A	
Q_{GS}	Gate-to-Source Charge			12	nC	V _{DS} = 50V	
Q_{GD}	Gate-to-Drain ('Miller') Charge			30.7		V _{GS} = 10V	
t _{d(on)}	Turn-On Delay Time			21		V _{DD} = 50V	
tr	Rise Time			145	ne	I _{D1} = 16A	
t _{d(off)}	Turn-Off Delay Time			64	ns	$R_G = 9.1\Omega$	
t _f	Fall Time			105		V _{GS} = 10V	
Ls +L _D	Total Inductance		6.8		nH	Measured from drain lead (6mm/0.25in. from package) to source lead (6mm/0.25in. from package)	
C _{iss}	Input Capacitance		1660			V _{GS} = 0V	
Coss	Output Capacitance		550		pF	V _{DS} = 25V	
C _{rss}	Reverse Transfer Capacitance		120			f = 1.0 MHz	

Source-Drain Diode Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)			16	۸	
I _{SM}	Pulsed Source Current (Body Diode) ①			100	Α	
V_{SD}	Diode Forward Voltage			1.5	V	$T_J = 25^{\circ}C, I_S = 16A, V_{GS} = 0V$
t _{rr}	Reverse Recovery Time			400	ns	$T_J = 25^{\circ}C, I_F = 16A, V_{DD} \le 50V$
Q _{rr}	Reverse Recovery Charge			2.4	μC	di/dt = 100A/µs ④
Ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Thermal Resistance

Symbol	Parameter	Min.	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case			1.25	
$R_{\theta CS}$	Case-to-sink		0.21		°C/W
$R_{\theta JA}$	Junction-to-Ambient (Typical Socket Mount)			80	

Footnotes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- $^{\circ}$ V_{DD} = 25V, starting T_J = 25°C, L = 1.8mH, Peak I_L = 16A, V_{GS} = 10V.
- $\label{eq:local_sd} \mbox{\Im} \quad \mbox{I_{SD}} \, \leq 16 \mbox{A}, \, \mbox{di/dt} \, \leq \, 170 \mbox{$A/\mu s$}, \, \mbox{V_{DD}} \leq 100 \mbox{V}, \, \mbox{T_{J}} \leq 150 \mbox{$^{\circ}$C}.$

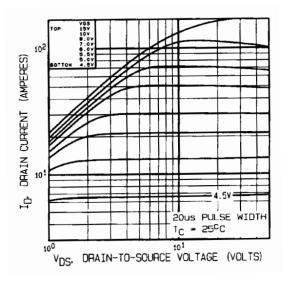


Fig 1. Typical Output Characteristics

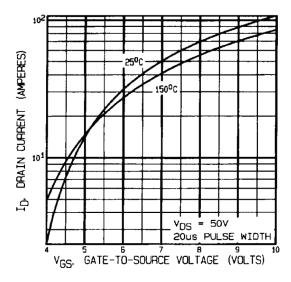


Fig 3. Typical Transfer Characteristics

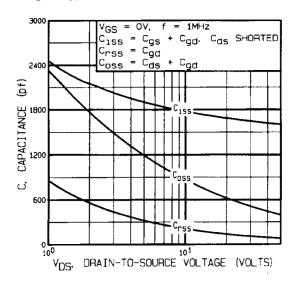


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

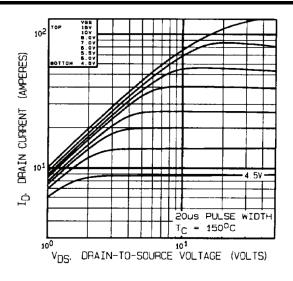


Fig 2. Typical Output Characteristics

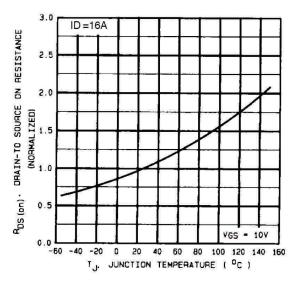


Fig 4. Normalized On-Resistance Vs. Temperature

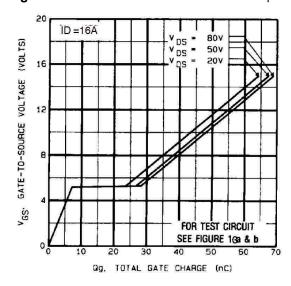


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

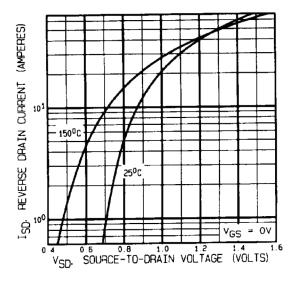


Fig 7. Typical Source-Drain Diode Forward Voltage

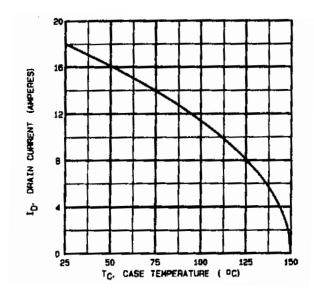


Fig 9. Maximum Drain Current Vs.Case Temperature

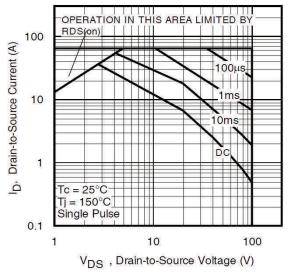


Fig 8. Maximum Safe Operating Area

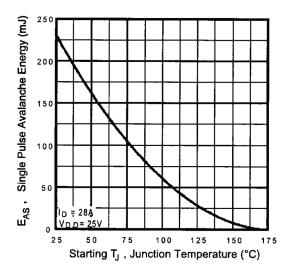


Fig 10. Maximum Avalanche Energy Vs. Drain Current

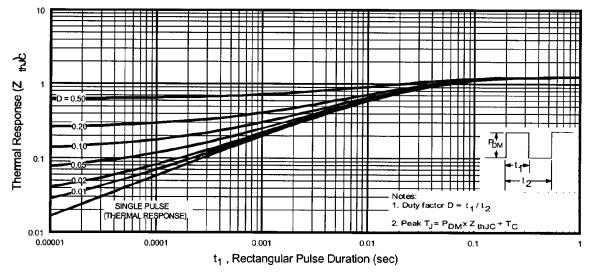


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

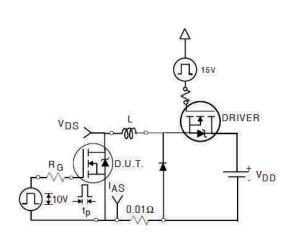


Fig 12a. Unclamped Inductive Test Circuit

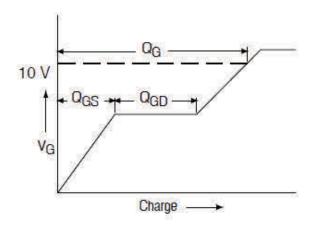


Fig 13a. Gate Charge Waveform

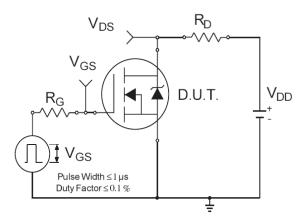


Fig 14a. Switching Time Test Circuit

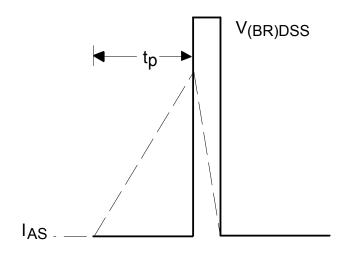


Fig 12b. Unclamped Inductive Waveforms

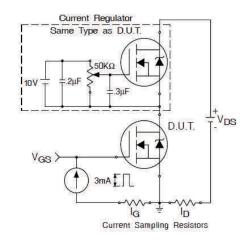


Fig 13b. Gate Charge Test Circuit

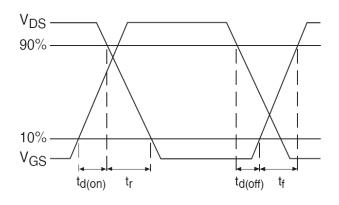
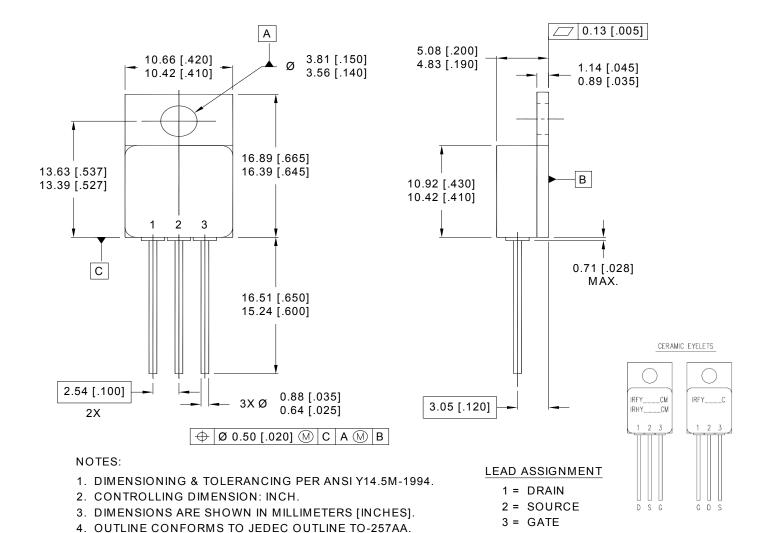


Fig 14b. Switching Time Waveforms



Case Outline and Dimensions - TO257AA





www.infineon.com/irhirel

Infineon Technologies Service Center: USA Tel: +1 (866) 951-9519 and International Tel: +49 89 234 65555

Leominster, Massachusetts 01453, USA Tel: +1 (978) 534-5776

San Jose, California 95134, USA Tel: +1 (408) 434-5000

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